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## EUROPEAN STANDARD

# EN 60749-2

## NORME EUROPÉENNE

## EUROPÄISCHE NORM

ICS 31.080.01

August 2002

Partly supersedes EN 60749 1999 + A1.2000 + A2 2001

English version

### Semiconductor devices -Mechanical and climatic test methods Part 2: Low air pressure (IEC 60749-2:2002)

Dispositifs à semiconducteurs -Méthodes d'essais mécaniques et climatiques Partie 2: Basse pression atmosphérique (CEI 60749-2:2002) Halbleiterbauelemente -Mechanische und klimatische Prüfverfahren Teil 2: Niedriger Luftdruck (IEC 60749-2:2002)

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# CENELEC

European Committee for Electrotechnical Standardization Comité Européen de Normalisation Electrotechnique Europäisches Komitee für Elektrotechnische Normung

Central Secretariat: rue de Stassart 35, B - 1050 Brussels

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EN 60749-2:2002

- 2 -

#### Foreword

The text of document 47/1601/FDIS, future edition 1 of IEC 60749-2, prepared by IEC TC 47, Semiconductor devices, was submitted to the IEC-CENELEC parallel vote and was approved by CENELEC as EN 60749-2 on 2002-07-02.

This mechanical and climatic test method, as it relates to low air pressure, is a complete rewrite of the test contained in clause 3, chapter 3 of EN 60749:1999.

The following dates were fixed:

<ul> <li>latest date by which the EN has to be implemented at national level by publication of an identical national standard or by endorsement</li> </ul>	(dop)	2003-04-01
<ul> <li>latest date by which the national standards conflicting with the EN have to be withdrawn</li> </ul>	(dow)	2005-07-01
Annexes designated "normative" are part of the body of the standard.		

In this standard, annex ZA is normative. Annex ZA has been added by CENELEC.

#### **Endorsement notice**

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